Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/689,901	YACH, DAVID P.	
Examiner	Art Unit	
Yicun Wu	2165	

SEARCHED					
Class	Subclass	Date	Examiner		
707	1-10, 100- 104.1 200-206	6/15/2006	YW		
375	240	6/15/2006	YW		
341	107	6/15/2006	ΥW		
		-			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1			
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SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
inventor search (double patenting) uspto uspgpub epo jpo ibmtech derwent	6/15/2006	ΥW
acm ieee citeseer internet Search stratagy attached	6/15/2006	ΥW
consulted Apu mofiz	6/15/2006	ΥW